

At-speed functional built-in self-test methodology for processors [Electronic resource]

Ubar, Raimund-Johannes; Indus, Viljar; Kalmend, Oliver Proceedings of the IASTED International Conference on Engineering and Applied Science : December 27-29, 2012, Columbo, Sri Lanka 2012 / p. 168-172 : ill [CD-ROM]

Functional built-in self-test for processor cores in SoC

Ubar, Raimund-Johannes; Indus, Viljar; Kalmend, Oliver; Evertson, Teet; Orasson, Elmet 30th IEEE NORCHIP Conference : Copenhagen, Denmark, November 12-14, 2012 2012 / p. 1-4 : ill <https://ieeexplore.ieee.org/document/6403148>